10/578683

# IAP12 Rec'd PCT/PTO 09 MAY 2006

Customer No. 22,852 Attorney Docket No. 05823.0283

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re A	Application of:	)	
Hai W	on LEE et al.	)	O A . 4 . 1 4.
Applic	ation No.: Not Yet Assigned	)	Group Art Unit:
Filed:	May 9, 2006	)	Examiner:
For:	FABRICATION METHOD OF EXTREME ULTRAVIOLET RADIATION MASK MIRROR USING ATOMIC FORCE MICROSCOPE LITHOGRAPHY	)	

#### U.S. National Phase of International PCT Application No. PCT/KR2004/001363

MAIL STOP PCT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

### INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§1.56 and 1.97(b), applicants bring to the Examiner's attention the documents listed on attached Form PTO/SB/08 and cited in the enclosed international search report. Copies of the listed foreign patent document and listed non patent literature documents are attached. Applicants respectfully request that the Examiner consider the documents listed on attached Form PTO/SB/08 and indicate that they were considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed with the above-referenced application.

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This submission does not represent that a search has been made or that no

better art exists and does not constitute an admission that each or all of the listed

documents are material or constitute "prior art." If the Examiner applies any of the

documents as prior art against any claim in the application and applicants determine

that the cited documents do not constitute "prior art" under United States law, applicants

reserve the right to present to the Office the relevant facts and law regarding the

appropriate status of such documents. Applicants further reserve the right to take

appropriate action to establish the patentability of the disclosed invention over the listed

documents, should one or more of the documents be applied against the claims of the

present application.

If there is any fee due in connection with the filing of this Statement, please

charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,

GARRETT & DUNNER, L.L.P.

Dated: May 9, 2006

Ernest F. Chapman

Reg. No. 25,961

Enclosures

EFC/FPD/gah

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IDS Form PTO/SB/08: Substitute for form 1449A/PTO  INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Anolyf 578683		
				Application Number		
				Filing Date	May 9, 2006	
				First Named Inventor	Hai Won LEE	
31/	STATEMENT BY APPLICANT			Art Unit		
	(Use as many sheets	as necessary)		Examiner Name		
Sheet	1	of	1	Attorney Docket Number	05823.0283	

U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS						
Examiner Initials	Cite No.1	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number-Kind Code <sup>2</sup> (if known)				
		US-6,110,607	09-29-2000	Montcalm et al.		
		US-6,229,652 B1	05-08-2001	Bajt et al.		
		US-6,228,512 B1	05-08-2001	Bajt et al.		
		US-4,329,410	05-11-1982	Buckley		
		US-6,338,990 B1	01-15-2002	Yanai et al.		
		US-				

Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

	FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>		

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>		
		RYU; "METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE"; Korean Patent Abstracts of KR 1020000073498 A, May 12, 2000.			
		MATSUO et al.; "MANUFACTURE OF MASK FOR EXPOSURE TO X-RAY AND BLANK USED THEREWITH"; Patent Abstracts of Japan of JP 05-283323, October 29, 1993			
		SUNDERMANN et al.; "NANOPATTERNING OF Au ABSORBER FILMS ON Mo/Si EUV MULTILAYER MIRRORS BY STM LITHOGRAPHY IN SELF-ASSEMBLED MONOLAYERS"; Surface Science, Vol. 454-456, pages 1104-1109, (2000)			

Examiner	Date	
Signature	 Considered	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.